

VME Intensity Monitor - Feature #11015

Milestone # 10477 (New): ANUB Startup

Feature # 9396 (Assigned): Beam Energy Loss Devices

BEL end-of-flattop reading devices

11/26/2015 11:22 AM - John Diamond

Status:	Closed	Start date:	11/26/2015
Priority:	Normal	Due date:	
Assignee:	John Diamond	% Done:	100%
Category:		Estimated time:	0.00 hour
Target version:		Spent time:	2.75 hours
Description			
See:			
<ul style="list-style-type: none">I:BEL20, I:BEL21, I:BEL23, I:BEL29, I:BEL2A, I:BEL2B, I:BEL2D, I:BEL2ER:BELE0, R:BELE1, R:BELE2, R:BELE3, R:BELE9			
It might make sense to use cycle devices to sample BEL on these events.			
Also, devices for normalized and average BEL at end-of-flattop readings			

History

#1 - 12/20/2015 04:34 PM - John Diamond

Implemented EOF samples and an read accessor for returning the sample to ACNET.
Updated anubstartup with default EOF triggers.
Need to create a setting accessor to re-set the EOF delay.

#2 - 12/20/2015 09:38 PM - John Diamond

Implemented an accessor for reading & setting the EOF BEL sample time.

#3 - 12/20/2015 09:54 PM - John Diamond

- Status changed from New to Assigned
- Assignee set to John Diamond
- % Done changed from 0 to 80

Changed the SSDN device ID from 0x0020 to 0x002b and added a setting parameter to the following:

- Z:IBEL20
- Z:IBEL21
- Z:IBEL23
- Z:IBEL2A
- Z:RBELE3

#4 - 12/21/2015 10:53 AM - John Diamond

- Status changed from Assigned to Closed
- % Done changed from 80 to 100

Verified that the sample time can be changed via ACNET.